




Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/521,068	EZAWA ET AL.	
	Examiner	Art Unit	
	Matthew G. Kayrish	2627	

ISSUE CLASSIFICATION										
ORIGINAL				CROSS REFERENCE(S)						
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
720		643		720	640	742	719	725	738	739
INTERNATIONAL CLASSIFICATION										
G	1	1	B	23/03						
				/						
				/						
				/						
				/						

Matthew Greco Kayrish (Assistant Examiner) (Date)	 WILLIAM KORZUCH SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2600 (Primary Examiner) (Date)	Total Claims Allowed: 18
 (Legal Instruments Examiner) (Date)		O.G. Print Claim(s) 1
		O.G. Print Fig. 4

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant										<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47		
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